

## 🌐 Language skills

Հայերեն English Русский Українська

## 📖 Publications

*Article*

### **Analytics for AI Related Applications of Multidimensional Multitape Finite Automata**

Samvel SHOUKOURIAN, Tigran GRIGORYAN, Sevak AMIRKHANYAN

Electronics, Communications and Networks 2023 49-60

*Article*

### **Functional Safety Compliant Test & Repair Framework for System-on-Chip Lifecycle Management**

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

Mathematical Problems of Computer Science 2021 7-17

*Article*

### **Polynomial algorithm for equivalence problem of deterministic multitape finite automata**

Samvel K. Shoukourian, Hayk A. Grigoryan

Theoretical Computer Science 2020 120-132

*Article*

### **Memory Physical Aware Multi-Level Fault Diagnosis Flow**

SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

*Article*

### **Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism**

S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

*Article*

### **Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications**

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 25-28

*Article*

### **Automated Flow for Test Pattern Creation for IPs in SoC**

S. Shoukourian, G. Harutyunyan, D. Sargsyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 21-24

Article

**An Efficient Testing Methodology for Embedded Flash Memories**

S. Shoukourian, G. Harutyunyan, S. Martirosyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 422-425

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Article

**Security Issues in Test and Repair Infrastructure for Systems-on-Chip**

S. Shoukourian, G. Harutyunyan, G. Tshagharyan

Информационно-коммуникационные технологии в науке, производстве и образовании ICIT-2017 2017 114-122

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Conference

**An efficient approach for memory repair by reducing the number of spares.**

Vrezh Sargsyan, Valery A. Vardanian, Samvel K. Shoukourian, Yervant Zorian, Avetik Yessayan

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Conference

**Extending fault periodicity table for testing faults in memories under 20nm.**

Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

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Conference

**A power based memory BIST grouping methodology.**

Lusine Martirosyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Conference

**Overview study on fault modeling and test methodology development for FinFET-based memories.**

Grigor Tshagharyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Conference

**Securing Test Infrastructure of System-on-Chips**

S. Shoukourian, G.Tshagharyan, G.Harutyunyan, Y.Zorin

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Conference

**Armenia: Communicating to World Community in Electronic Test and Design**

Samvel Shoukourian, Yuri Shoukourian, Vladimir Sahakyan

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Patent

**Testing Electronic Memories Based on Fault and Test Algorithm Periodicity**

S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

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Patent

**FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS**

Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

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Patent

**DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES**

Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian

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